

#### 650V N-Channel Enhancement Mode MOSFET

#### Description

The AP4N65D/Y is silicon N-channel Enhanced

VDMOSFETs, is obtained by the self-aligned planar Technology

which reduce the conduction loss, improve switching

performance and enhance the avalanche energy. The transistor

can be used in various power switching circuit for system

#### **General Features**

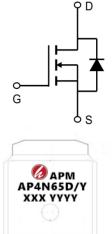
VDS =650V,ID =4A

RDS(ON) <2.4Ω@ VGS=10V

#### Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)







#### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP4N65D	TO-252-3L	AP4N65D XXX YYYY	2500
AP4N65Y	TO-251-3L	AP4N65Y XXX YYYY	1000

#### Absolute Maximum Ratings Tc = 25°C, unless otherwise noted

Parameter	Symbol	Value	Unit	
Drain-Source Voltage (V <sub>GS</sub> = 0V)		VDSS	650	V
Continuous Drain Current		ID	4	A
Pulsed Drain Current	(note1)	Ідм	16	A
Gate-Source Voltage		Vgss	±30	V
Single Pulse Avalanche Energy	(note2)	Eas	160	mJ
Avalanche Current	(note1)	lar	4	A
Repetitive Avalanche Energy	(note1)	Ear	20	mJ
Power Dissipation (T <sub>C</sub> = 25°C)		PD	36	W
Operating Junction and Storage Temperature Range		TJ, Tstg	-55~+150	°C
Thermal Resistance, Junction-to-Case		RthJC	3.47	K/W
Thermal Resistance, Junction-to-Ambien	t	RthJA	62.5	



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#### Electrical Characteristics (T<sub>A</sub>=25<sup>°</sup>Cunless otherwise noted)

Parameter Symbol Test Conditions		Test Conditions	Min.	Туре	Max	Unit
Drain-Source Breakdown Voltage	V(BR)DSS	$V_{GS}$ = 0V, I <sub>D</sub> = 250µA	650			V
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = 650V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 25°C			1	μA
Gate-Source Leakage	lgss	$V_{GS}$ = $\pm 30V$			±100	nA
Gate-Source Threshold Voltage	VGS(th)	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	3.0		4.0	V
Drain-Source On-Resistance (Note3)	RDS(on)	$V_{GS}$ = 10V, $I_D$ = 2.0A		2	2.4	Ω
Input Capacitance	Ciss			580		pF
Output Capacitance	Coss	$V_{GS} = 0V,$ $V_{DS} = 25V,$		69.5		
Reverse Transfer Capacitance	Crss	f = 1.0MHz		10.9		
Total Gate Charge	Qg			15		nC
Gate-Source Charge	Q <sub>gs</sub>	$V_{DD} = 520V, I_D = 4.0A,$ $V_{GS} = 10V$		2.5		
Gate-Drain Charge	Q <sub>gd</sub>			7.5		
Turn-on Delay Time	td(on)			12		ns
Turn-on Rise Time	tr	V <sub>DD</sub> = 400V, I <sub>D</sub> =4.0A,		22		
Turn-off Delay Time	td(off)	$R_{\rm G} = 25 \ \Omega$		50		
Turn-off Fall Time	t <sub>f</sub>			48		
Continuous Body Diode Current	ls				4	
Pulsed Diode Forward Current	Іѕм	T <sub>C</sub> = 25 °C			16	A
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25°C, I <sub>SD</sub> = 4.0A, V <sub>GS</sub> = 0V			1.4	V
Reverse Recovery Time	t <sub>rr</sub>	V <sub>GS</sub> = 0V,I <sub>S</sub> = 4.0A,		250		ns
Reverse Recovery Charge	Qrr	di⊧/dt =100A /µs		3.5		μC

#### Notes

1. Repetitive Rating: Pulse width limited by maximum junction temperature

2.  $I_{AS} = 4A$ ,  $V_{DD} = 50V$ ,  $R_G = 25 \Omega$ , Starting  $T_J = 25 \text{ °C}$ 

3. Pulse Test: Pulse width  $\leq$  300µs, Duty Cycle  $\leq$  1%

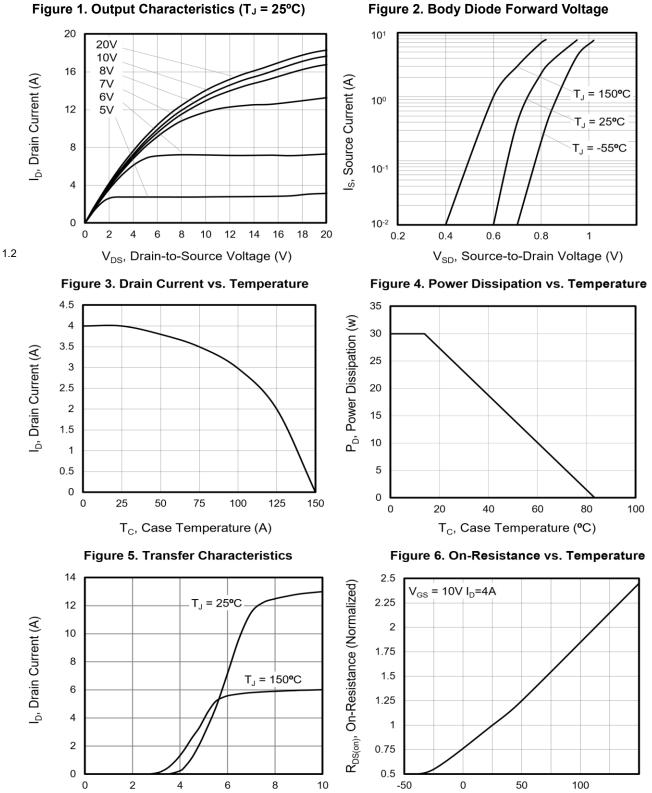
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Typical Characteristics T<sub>J</sub> = 25°C, unless otherwise noted

V<sub>GS</sub>, Gate-to-Source Voltage (V)

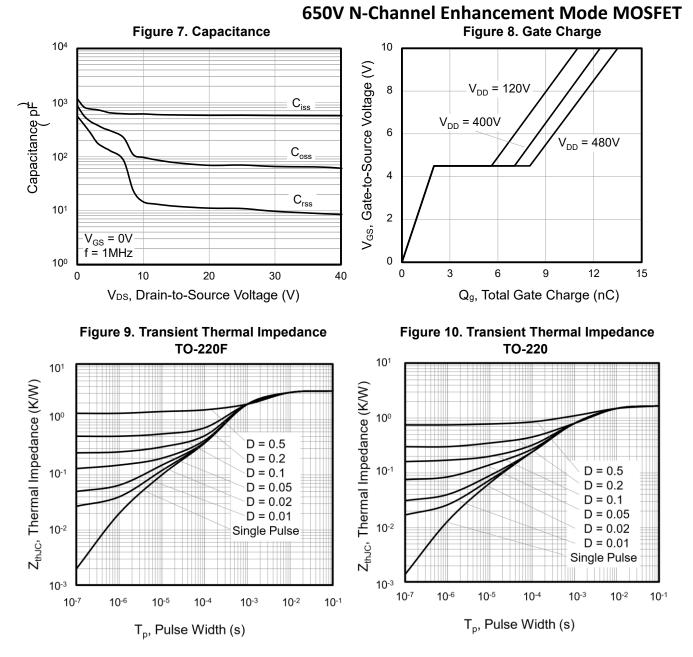


T<sub>J</sub>, Junction Temperature (°C)

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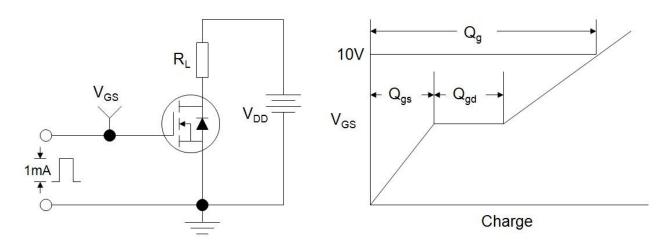


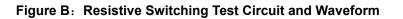


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Figure A: Gate Charge Test Circuit and Waveform





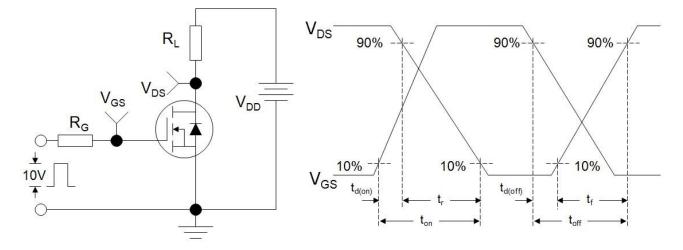


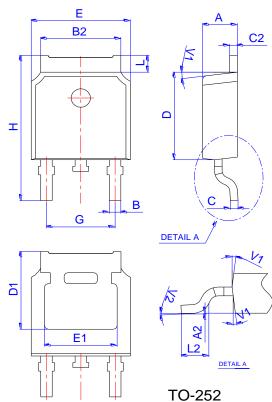
Figure C: Unclamped Inductive Switching Test Circuit and Waveform

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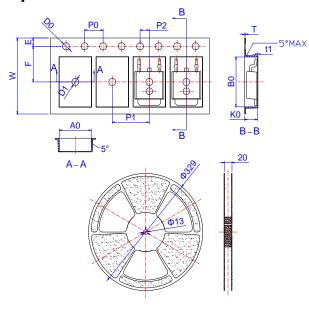
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## Package Mechanical Data



	Dimensions						Dime			
Ref.		Millimeters			Inches					
	Min.	Тур.	Max.	Min.	Тур.	Max.				
А	2.10		2.50	0.083		0.098				
A2	0		0.10	0		0.004				
В	0.66		0.86	0.026		0.034				
B2	5.18		5.48	0.202		0.216				
С	0.40		0.60	0.016		0.024				
C2	0.44		0.58	0.017		0.023				
D	5.90		6.30	0.232		0.248				
D1	5.30REF			0.209REF						
E	6.40		6.80	0.252		0.268				
E1	4.63			0.182						
G	4.47		4.67	0.176		0.184				
н	9.50		10.70	0.374		0.421				
L	1.09		1.21	0.043		0.048				
L2	1.35		1.65	0.053		0.065				
V1		7°			7°					
V2	0°		6°	0°		6°				

### **Reel Spectification-TO-252**



	Dimensions						
Ref.	Millimeters			Inches			
	Min.	Тур.	Max.	Min.	Тур.	Max.	
W	15.90	16.00	16.10	0.626	0.630	0.634	
E	1.65	1.75	1.85	0.065	0.069	0.073	
F	7.40	7.50	7.60	0.291	0.295	0.299	
D0	1.40	1.50	1.60	0.055	0.059	0.063	
D1	1.40	1.50	1.60	0.055	0.059	0.063	
P0	3.90	4.00	4.10	0.154	0.157	0.161	
P1	7.90	8.00	8.10	0.311	0.315	0.319	
P2	1.90	2.00	2.10	0.075	0.079	0.083	
A0	6.85	6.90	7.00	0.270	0.271	0.276	
B0	10.45	10.50	10.60	0.411	0.413	0.417	
K0	2.68	2.78	2.88	0.105	0.109	0.113	
Т	0.24		0.27	0.009		0.011	
t1	0.10			0.004			
10P0	39.80	40.00	40.20	1.567	1.575	1.583	

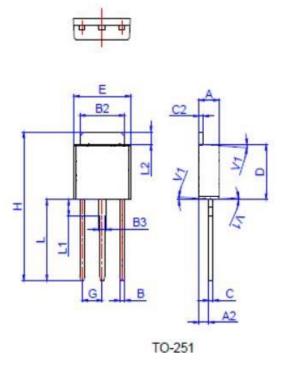
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### Package Mechanical Data



Ref.	Dimensions								
	9	Millimete	rs	Inches					
	Min.	Тур.	Max.	Min.	Тур.	Max			
A	2.20	1	2.40	0.086		0.095			
A2	0.90		1.20	0.035		0.047			
в	0.55		0.65	0.022		0.026			
B2	5.10	1	5.40	0.200		0.213			
B3	0.76		0.85	0.030		0.033			
С	0.45		0.62	0.018		0.024			
C2	0.48		0.62	0.019		0.024			
D	6.00		6.20	0.236		0.244			
E	6.40		6.70	0.252		0.264			
G		2.30			0.091				
н	16.0		17.0	0.630		0.669			
L	8.90		9.40	0.350		0.370			
L1	1.80		1.90	0.071		0.075			
L2	1.37		1.50	0.054		0.059			
V1		4°			4°				

### Package Information -TO-251

OUTLINE	TUBE	INNER BOX	PER CARTON
	(PCS)	(PCS)	(PCS)
TUBE	80	4,000	32,000



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